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September 2007



# FGPF30N30TD 300V, 30A PDP Trench IGBT

#### Features

- · High current capability
- Low saturation voltage: V<sub>CE(sat)</sub> =1.4V @ I<sub>C</sub> = 20A
- High input impedance
- · Fast switching
- · RoHS complaint

#### **Applications**

PDP System



## **General Description**

Using Novel Trench IGBT Technology, Fairchild's new sesries of trench IGBTs offer the optimum performance for PDP applications where low conduction and switching losses are essential.



#### **Absolute Maximum Ratings**

Symbol	Description		Ratings	Units
V <sub>CES</sub>	Collector to Emitter Voltage		300	V
V <sub>GES</sub>	Gate to Emitter Voltage		± 30	V
I <sub>C pulse (1)</sub>	Pulsed Collector Current	@ T <sub>C</sub> = 25°C	80	A
I <sub>F</sub>	Diode Continuous Forward Current	@ T <sub>C</sub> = 100°C	10	A
I <sub>FM</sub>	Diode Maximum Forward Current		40	A
P <sub>D</sub>	Maximum Power Dissipation	@ T <sub>C</sub> = 25°C	44.6	W
· D	Maximum Power Dissipation	@ T <sub>C</sub> = 100°C	17.8	W
TJ	Operating Junction Temperature		-55 to +150	°C
T <sub>stg</sub>	Storage Temperature Range		-55 to +150	°C
TL	Maximum Lead Temp. for soldering Purposes, 1/8" from case for 5 seconds		300	°C

### **Thermal Characteristics**

Symbol	Parameter	Тур.	Max.	Units
$R_{\theta JC}(IGBT)$	Thermal Resistance, Junction to Case	-	2.8	°C/W
$R_{\theta JC}(DIODE)$	DIODE) Thermal Resistance, Junction-to-Case for Diode		3.0	°C/W
$R_{ ext{ heta}JA}$	Thermal Resistance, Junction to Ambient	-	62.5	°C/W

Notes :

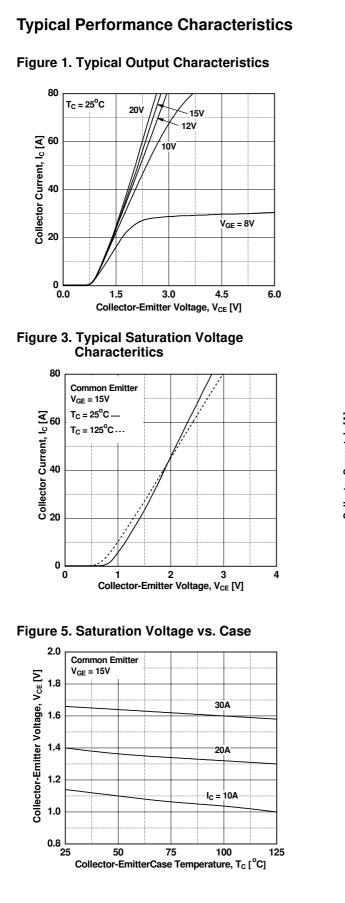
(1) Repetitive tese, Pulse width = 100usec, Duty = 0.1

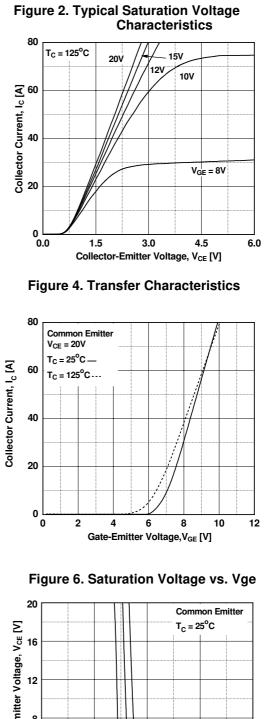
\* Ic\_pluse limited by max Tj

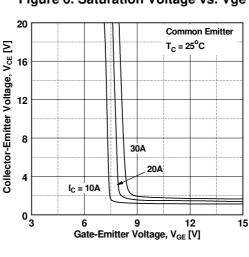
		Pac	PackagingackageTyper0-220FRail / Tube		Qty per Tube		Max Qty per Box		
		TO-							
Electric	al Cha	racteristics of t	ho ICI	BT					
Symbol		Parameter		-	Conditions	Min.	Тур.	Max.	Units
-,							- 71		
Off Charac	teristics								
BV <sub>CES</sub>	Collector	to Emitter Breakdown V	oltage V	/ <sub>GE</sub> = 0V, I <sub>C</sub>	; = 250μA	300	-	-	V
ΔΒV <sub>CES</sub> / ΔΤ <sub>J</sub>	Temperat Voltage	ure Coefficient of Break	<sup>down</sup> v	/ <sub>GE</sub> = 0V, I <sub>C</sub>	; = 250μA	-	0.26	-	V/ºC
I <sub>CES</sub>	Collector	Cut-Off Current	V	$V_{CE} = V_{CES}$	V <sub>GE</sub> = 0V	-	-	100	μA
I <sub>GES</sub>	G-E Leak	age Current	٧	V <sub>GE</sub> = V <sub>GES</sub>	, V <sub>CE</sub> = 0V	-	-	±400	nA
On Charac	teristics								
V <sub>GE(th)</sub>	G-E Thre	shold Voltage	١	I <sub>C</sub> = 250μA, V <sub>CE</sub> = V <sub>GE</sub>		3.0	4.5	5.5	V
	Collector to Emitter Saturation Voltage		I	<sub>C</sub> = 10A, V <sub>G</sub>	<sub>E</sub> = 15V	-	1.2	1.5	V
			I	<sub>C</sub> = 20A, V <sub>G</sub>	<sub>E</sub> = 15V	-	1.4	-	V
V <sub>CE(sat)</sub>				$I_{C} = 30A, V_{GE} = 15V,$ $T_{C} = 25^{\circ}C$		-	1.7	-	V
				$I_{C} = 30A, V_{GE} = 15V,$ $T_{C} = 125^{\circ}C$		-	1.6	-	V
Dynamic C	haracteris	atics					1		1
C <sub>ies</sub>	Input Cap					-	1540		pF
C <sub>oes</sub>	Output Ca	apacitance		V <sub>CE</sub> = 30V, V <sub>GE</sub> = 0V, f = 1MHz		-	65		pF
C <sub>res</sub>		Transfer Capacitance	†			-	55		pF
Switching	Character	istics					1		1
t <sub>d(on)</sub>		Delay Time				-	22		ns
ŧ	Rise Time			/ <sub>CC</sub> = 200V		-	33		ns
t <sub>d(off)</sub>		Delay Time		$R_{G} = 20\Omega, V$		-	130		ns
t <sub>f</sub>	Fall Time	,	"	Inductive Load, T <sub>C</sub> = 25°C		-	180	300	ns
t <sub>d(on)</sub>		Delay Time				-	21		ns
t <sub>r</sub>	Rise Time		V	$V_{CC} = 200V, I_C = 20A,$ - $R_G = 20\Omega, V_{GE} = 15V,$ Inductive Load, $T_C = 125^{\circ}C$		-	34		ns
t <sub>d(off)</sub>		Delay Time	F			-	140		ns
t <sub>f</sub>	Fall Time	•	["		, 10 - 120 0	-	260		ns
Q <sub>g</sub>	Total Gate					-	65		nC
Q <sub>ge</sub>		mitter Charge		<sub>CE</sub> = 200V	I <sub>C</sub> = 20A,	-	10		nC
Q <sub>gc</sub>		Collector Charge	V	V <sub>GE</sub> = 15V		_	26		nC

Symbol	Parameter	Test Conditions		Min.	Тур.	Max.	Units
V <sub>FM</sub> Diode Forward Voltage	Diodo Ecrward Voltago	I <sub>E</sub> = 10A	$T_{C} = 25^{\circ}C$		1.1	1.4	v
		T <sub>C</sub> = 125°C		0.9		ľ	
+	Diode Reverse Recovery Time	I <sub>F</sub> = 10A dI/dt = 200A/μs Diode Forward Voltage	$T_{C} = 25^{\circ}C$		22		- ns - A - nC
t <sub>rr</sub>	Didde Heverse Hecovery Time		T <sub>C</sub> = 125°C		35		
I <sub>rr</sub>	Diode Peak Reverse Recovery Cur- rent		$T_{C} = 25^{\circ}C$		2.7		
			T <sub>C</sub> = 125°C		5.6		
Q <sub>rr</sub>	Diode Reverse Recovery Charge		$T_{C} = 25^{\circ}C$		29.7		
			T <sub>C</sub> = 125°C		98		

## Electrical Characteristics of DIODE T<sub>C</sub> = 25°C unless otherwise noted

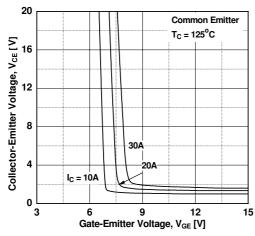




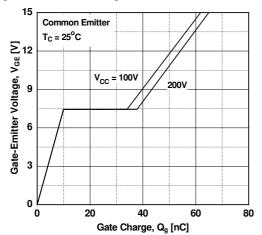


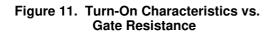
## Typical Performance Characteristics (Continued)

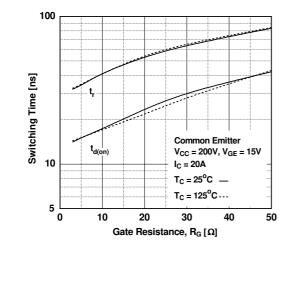




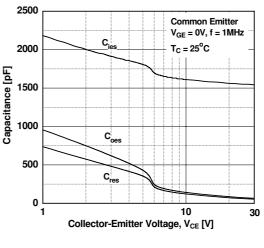
**Figure 9. Gate Charge Characteristics** 











**Figure 10. SOA Characteristics** 

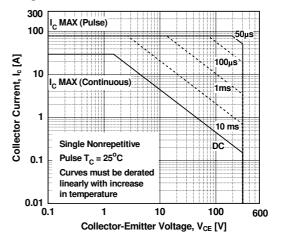
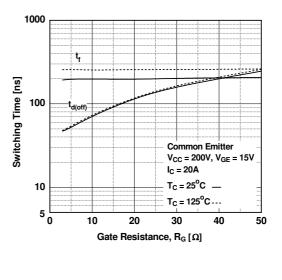


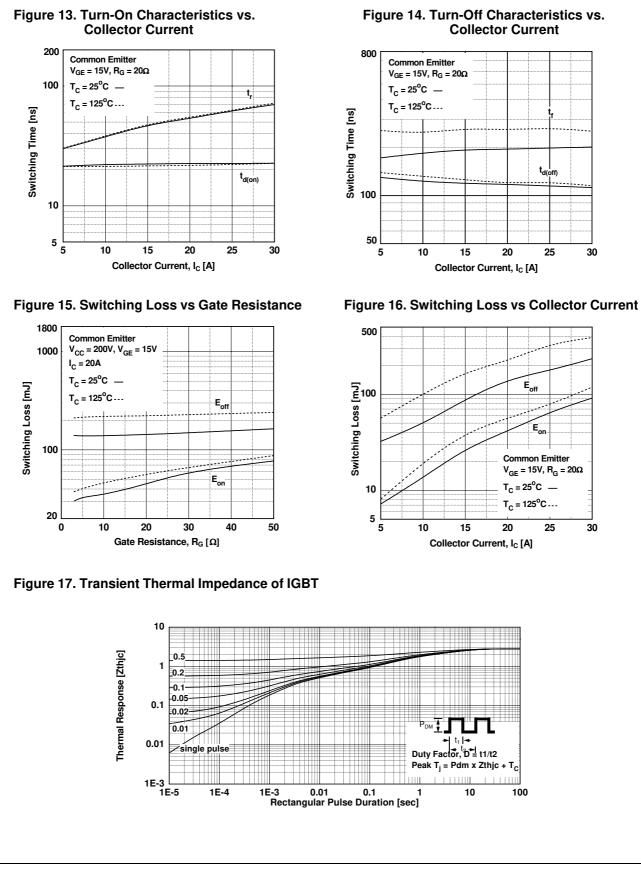
Figure 12. Turn-Off Characteristics vs. Gate Resistance



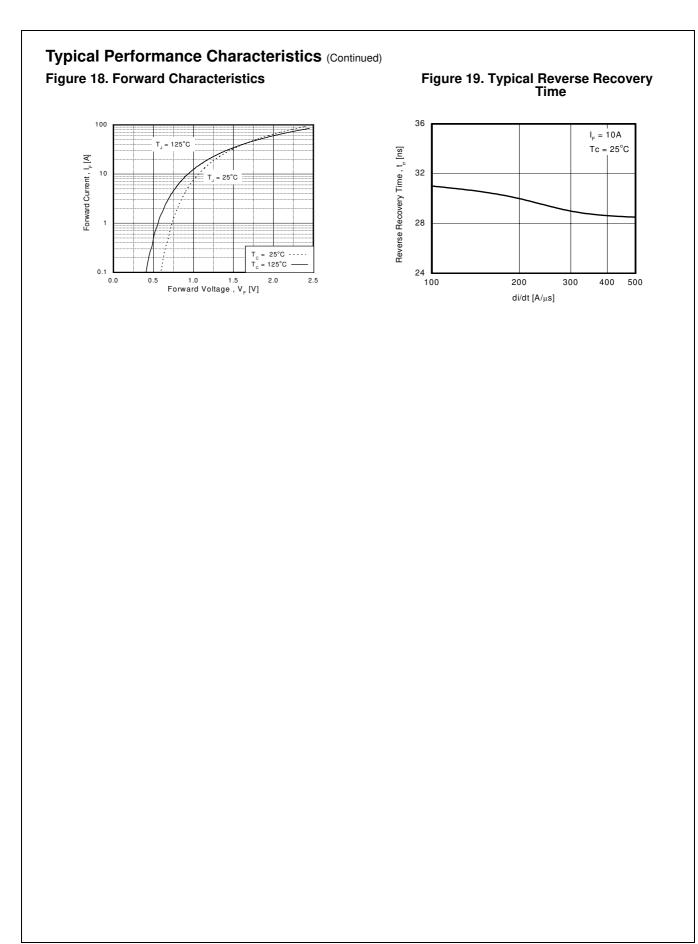
FGPF30N30TD 300V, 30A PDP Trench IGBT

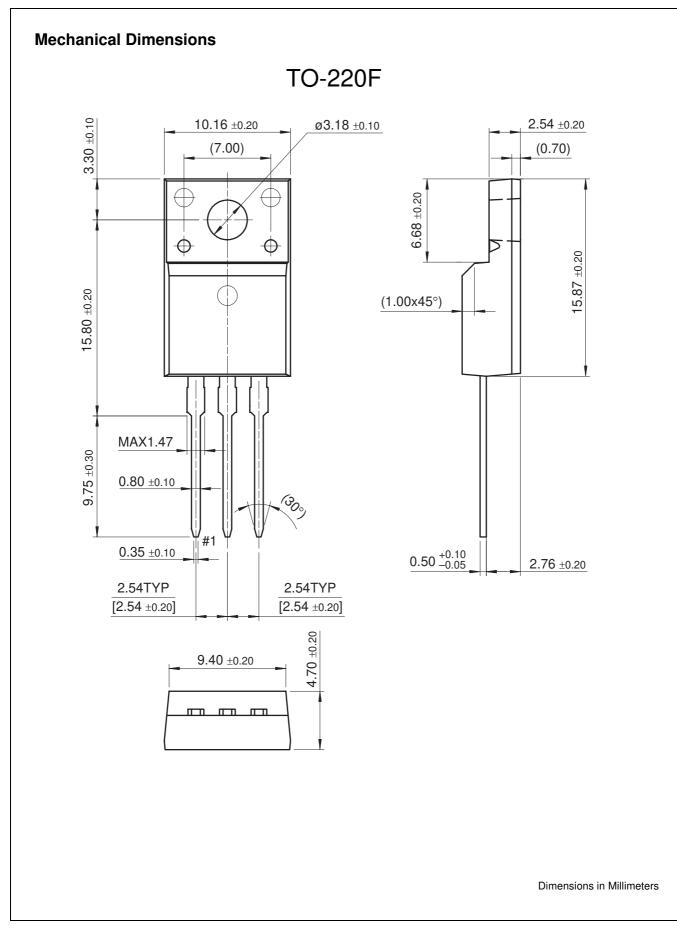
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Typical Performance Characteristics (Continued)







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